


<b>Search Notes</b> 	<b>Application/Control No.</b> 10556911	<b>Applicant(s)/Patent Under Reexamination</b> YONEYAMA ET AL.
	<b>Examiner</b> Benny Lee	<b>Art Unit</b> 2817

SEARCHED			
Class	Subclass	Date	Examiner
333	26, 248	22 September 2008	BTL

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
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